

Application/Control No.

10/060,994

Examiner

Conrad J. DeWitte

Applicant(s)/Patent Under Reexamination YI, LELAND

Art Unit
Page 1 of 1

U.S. PATENT DOCUMENTS

*	. ,	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-2002/0080231 A1	06-2002	Feierbach, Wolfgang	348/14.02
	В	US-5,629,722 A	05-1997	Oh, Yong G.	345/467
.gaagt.	Ų	US-6,597,343 B1	07-2003	Akiyama et al.	345/168
-	D	US-6,473,631 B1	10-2002	Siddoway et al.	455/575.1
	Е	US-5,841,424 A	11-1998	Kikinis, Dan	345/168
	F	US-4,888,648 A	12-1989	Takeuchi et al.	386/52
	O	US-4,291,198 A	09-1981	Anderson et al.	379/93.17
	Ι	US-2003/0197685 A1	10-2003	Yi, Leland	345/168
	_	US-2003/0006957 A1	01-2003	Colantonio et al.	345/156
	J	US-2002/0160724 A1	10-2002	Arai et al.	455/90
	К	US-2001/0013891 A1	08-2001	HAMILTON, CHRIS	348/14.08
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Ν					
	0			-		
	Р					
	α					
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	υ	
	V	
	w	
	x	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

